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				Application Number	10728068	
				Filing Date	12/4/03	
				First Named Inventor	Steinmann et al.	
				Group Art Unit	2826	
Examiner Name	Dolan					
Sheet	1	of	1	Attorney Docket No.	TI-36776	

U.S. PATENT DOCUMENTS						
Exam. Initials*	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Doc.	Date of Pub. of Cited Doc. (mm-dd-yyyy)	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
NMD	AA	6,497,824	B1	Chen et al.	12/24/2002	Entire Document
	AB					

FOREIGN PATENT DOCUMENTS								
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OTHER PRIOR ART - NON PATENT LITERATURE DOCUMENTS					T ²
Exam. Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.			
NMD	CA	"Characterization of Bolometers Based on Polycrystalline Silicon Germanium Alloys", S. SEDKY, P. FIORINI, M. CAYMAX, C. BAERT, L. HERMANS and R. MERTENS, IEEE Electron Device Letters, Vol. 19, No. 10, October 1998, pp.376-378.			
NMD	CB	"Analysis of Distributed Resistance Effects in MOS Transistors", JOHN HORAN, COLIN LYDEN, ALAN MATHEWSON, CIARAN C. CAHILL and W. A. LANE, IEEE Transactions on Computer Aided Design, Volume 8, No. 1, January 1989, pp. 41-45.			
NMD	CC	"A Technique for Electrically Measuring the Thermal Resistance of GaAs Bulk Resistors", Edwin Sabin, John Scarpulla, Yeong-Chang Chou and Gene Shlimamoto, GaAs Reliability Workshop, 2000, Proceedings, pp. 65-69.			
NMD	CD	"Heat Transport in Thin Dielectric Films", S.M. LEE and DAVID G. CAHILL, J. Appl. Phys., American Institute of Physics, Volume 81, March 1997, pp. 2590-2595.			
NMD	CE	"Effect of Thickness on the Transverse Thermal conductivity of Thin Dielectric Films", A.J. GRIFFIN, JR., F.R. BROTZEN, and P.J. LOOS, J. Appl. Phys., American Institute of Physics, Volume 75, April 1994, pp. 3761-3764.			
NMD	CF	"Integration of Thin Film MIM Capacitors and Resistors into Copper Metallization Based RF-CMOS and Bi-CMOS Technologies", PETER ZURCHER, PRASAD ALLURI, PEIR CHU, ALAIN DUVALLET, CHRIS HAPP, RASHAUNDA HENERSON, JOHN MENDONCA, MATTHEW KIM, MICHAEL PETRAS, MARK RAYMOND, TOM REMMEL, DOUG ROBERTS, BOB STEIMLE, JIM STIPANUK, SHERRY STRAUB, TERRY SPARKS, MARC TARABBIA, HELENE THIBIEROZ and MEL MILLER, Electron Devices Meeting, 2000, IEDM Technical Digest International, 2000, pp. 153-156.			
NMD	CG	Temperature Variation, "The Art of Analog Layout", A. HASTING, Prentice Hall, 1 st Edition, December 2000, P. 164.			
	CH				

Examiner Signature		Date Considered	05/11/2005
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